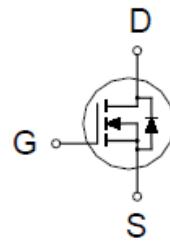
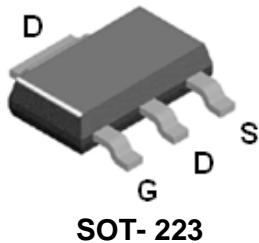


# P0320AL

## N-Channel Enhancement Mode MOSFET

### PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
200V	1.1Ω @ $V_{GS} = 10V$	1A



### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	$V_{GS}$	$\pm 30$	V
Continuous Drain Current $T_A = 25^\circ C$	$I_D$	1	A
$T_A = 70^\circ C$		0.8	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	4	
Avalanche Current	$I_{AS}$	2	
Avalanche Energy	$E_{AS}$	53	mJ
Power Dissipation $T_A = 25^\circ C$	$P_D$	2.5	W
$T_A = 70^\circ C$		1.6	
Operating Junction & Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		50	°C / W

<sup>1</sup>Pulse width limited by maximum junction temperature.

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### ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)

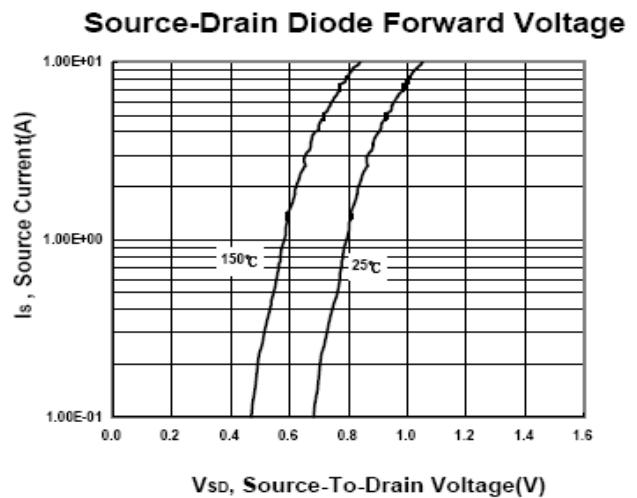
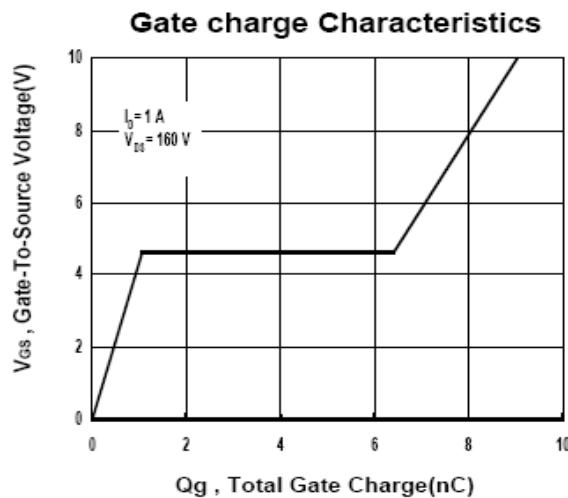
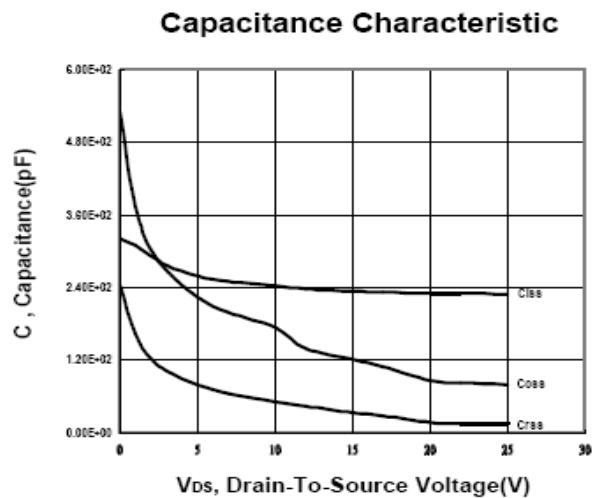
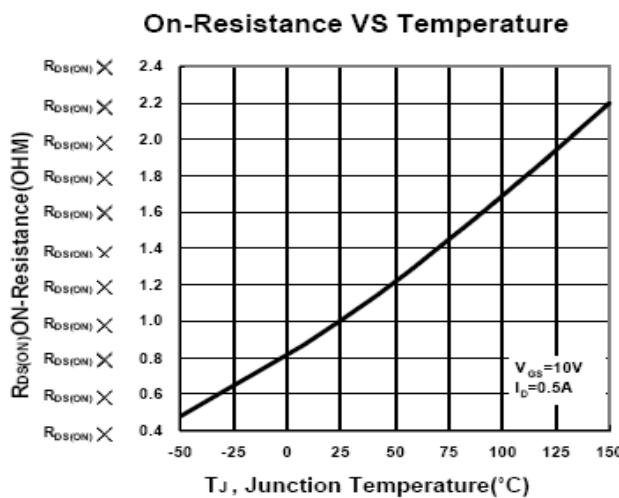
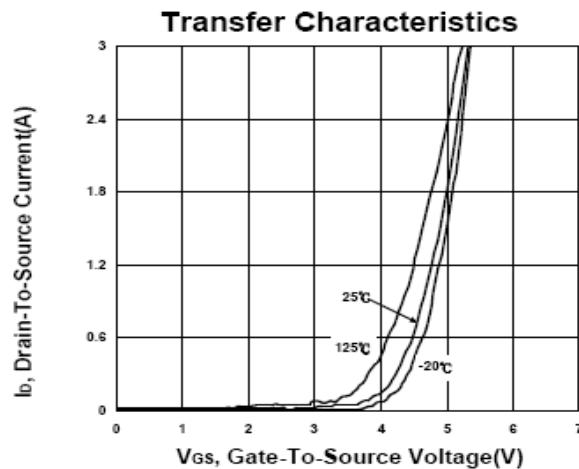
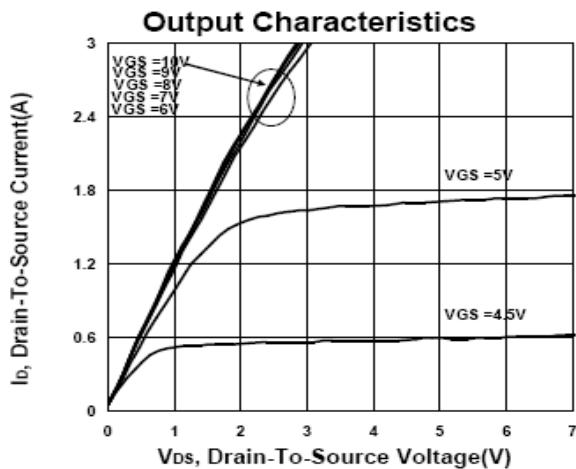
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	200			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	2	3.2	4	
Gate-Body Leakage	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 30\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 200\text{V}, V_{\text{GS}} = 0\text{V}$			25	$\mu\text{A}$
		$V_{\text{DS}} = 160\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			250	
Drain-Source On-State Resistance <sup>1</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 0.5\text{A}$		0.8	1.1	$\Omega$
Forward Transconductance <sup>1</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = 5\text{V}, I_D = 0.5\text{A}$		1.5		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		229		pF
Output Capacitance	$C_{\text{oss}}$			80		
Reverse Transfer Capacitance	$C_{\text{rss}}$			16		
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{\text{DS}} = 160\text{V}$ $I_D = 1\text{A}, V_{\text{GS}} = 10\text{V}$		9		nC
Gate-Source Charge <sup>2</sup>	$Q_{\text{gs}}$			1.2		
Gate-Drain Charge <sup>2</sup>	$Q_{\text{gd}}$			5.5		
Turn-On Delay Time <sup>2</sup>	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 100\text{V}, I_D \approx 1\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GS}} = 25\Omega$		50		nS
Rise Time <sup>2</sup>	$t_r$			300		
Turn-Off Delay Time <sup>2</sup>	$t_{\text{d}(\text{off})}$			80		
Fall Time <sup>2</sup>	$t_f$			180		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				1	A
Forward Voltage <sup>1</sup>	$V_{\text{SD}}$	$I_F = 0.5\text{A}, V_{\text{GS}} = 0\text{V}$			1.6	V
Reverse Recovery Time	$t_{\text{rr}}$	$I_F = 1\text{ A}, dI/dt = 100\text{A} / \mu\text{s}$		119		nS
Reverse Recovery Charge	$Q_{\text{rr}}$			325		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

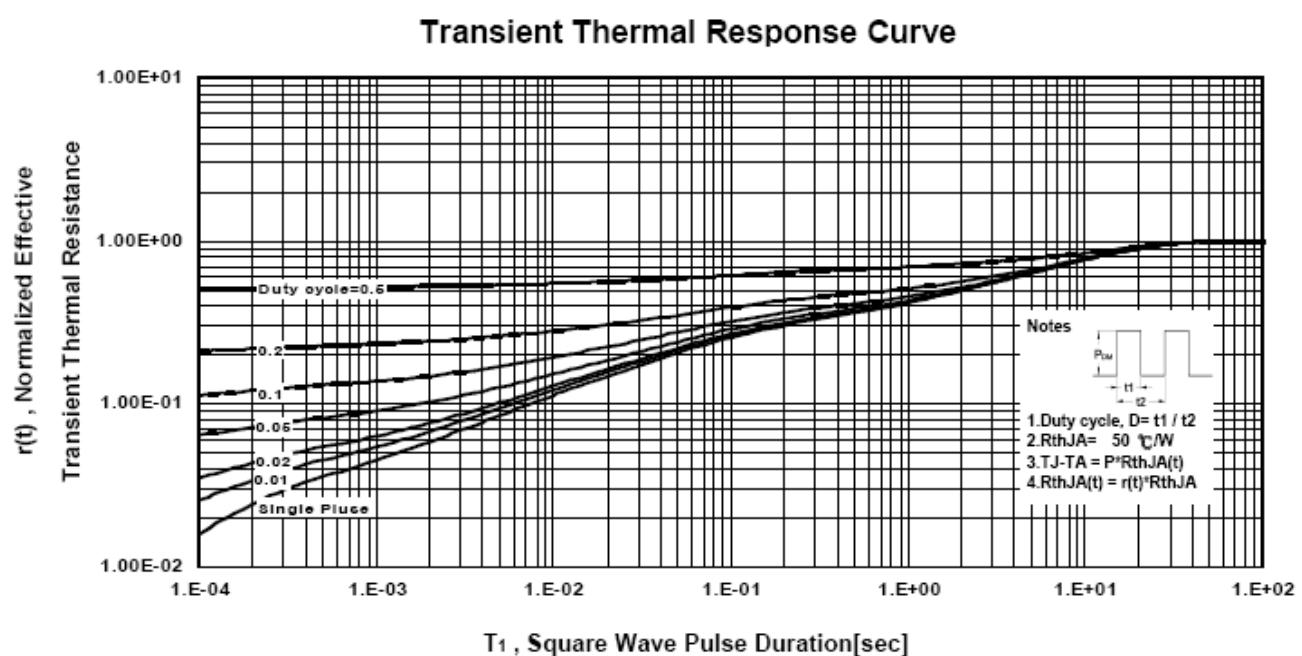
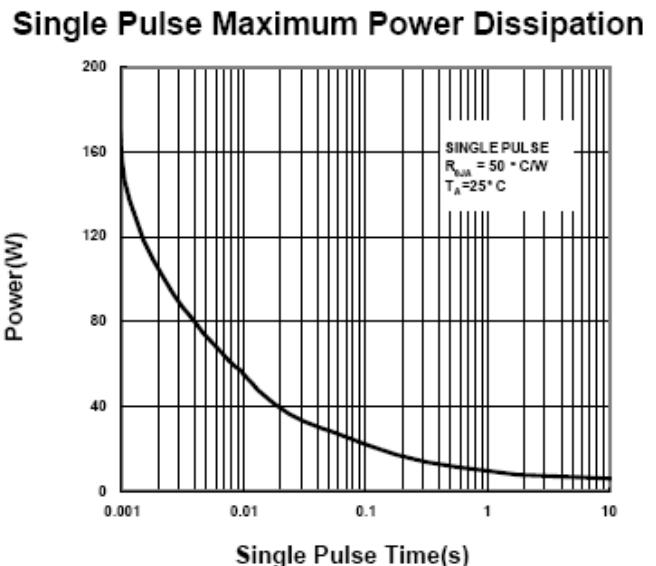
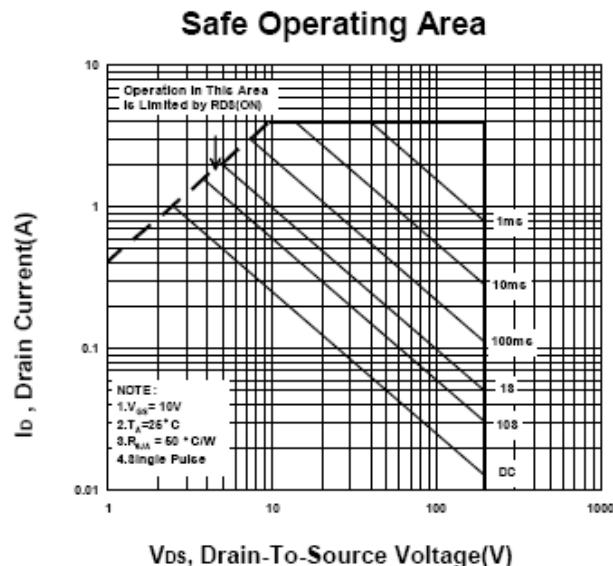
## P0320AL

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## P0320AL

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#### SOT-223 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	0.60	0.76	0.84	H	3.30	3.50	3.70
B	6.70	7.00	7.30	I	0.50	1.00	1.20
C	2.85	3.00	3.10	J	0.23	0.3	0.4
D	2.25	2.30	2.35	K	0°		10°
E	4.35	4.60	4.85	L	0	0.1	0.2
F	1.40	1.60	1.80	M			
G	6.30	6.50	6.80	N			

